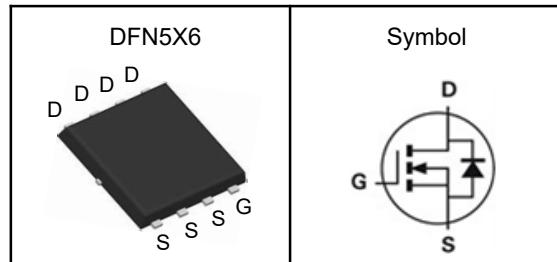


N-Channel Enhancement Mode MOSFET

Features

- Fast switching speed
- Reliable and Rugged
- ROHS Compliant
- 100% UIS and Rg Tested

Pin Description



Applications

- Power Management in Desktop Computer
- DC/DC Converters

V_{DSS}	40	V
$R_{DS(ON)-Typ}$	3.5	$m\Omega$
I_D	80	A

Absolute Maximum Ratings ($T_c=25^\circ C$, Unless Otherwise Noted)

Symbol	Parameter	Rating	Unit
V_{DSS}	Drain-Source Voltage	40	V
V_{GSS}	Gate-Source Voltage	± 20	V
T_J	Maximum Junction Temperature	-55 to 150	$^\circ C$
T_{STG}	Storage Temperature Range	-55 to 150	$^\circ C$
EAS	Single Pulse Avalanche Energy ^③	121	mJ
$I_{DM}^{①}$	Pulse Drain Current Tested	320	A
I_D	Continuous Drain Current	$T_c=25^\circ C$	A
P_D	Maximum Power Dissipation	$T_c=25^\circ C$	W

Thermal Characteristics

Symbol	Parameter	Rating	Unit
$R_{\theta JA}$	Thermal Resistance-Junction to Ambient	30	$^\circ C/W$
$R_{\theta JC}$	Thermal Resistance Junction-Case ₁	1.92	$^\circ C/W$

Note ① : Max. current is limited by bonding wire.

Note ② : UIS tested and pulse width are limited by maximum junction temperature 150°C.

Note ③ : Surface Mounted on 1in² FR-4 board with 1oz.

N-Channel Enhancement Mode MOSFET

Electrical Characteristics ($T_J=25^\circ\text{C}$, Unless Otherwise Noted)

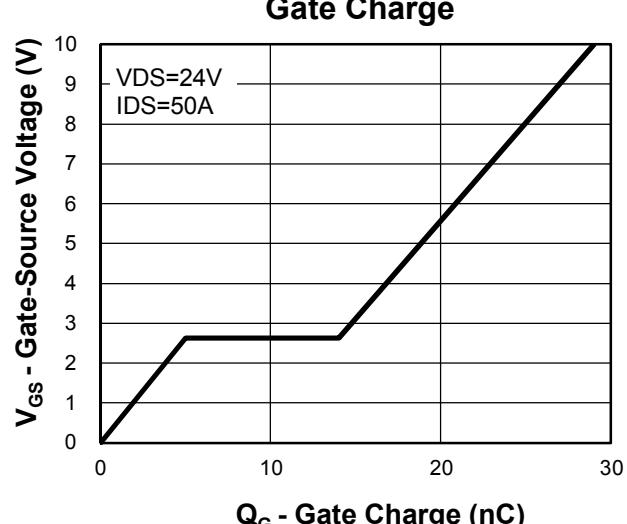
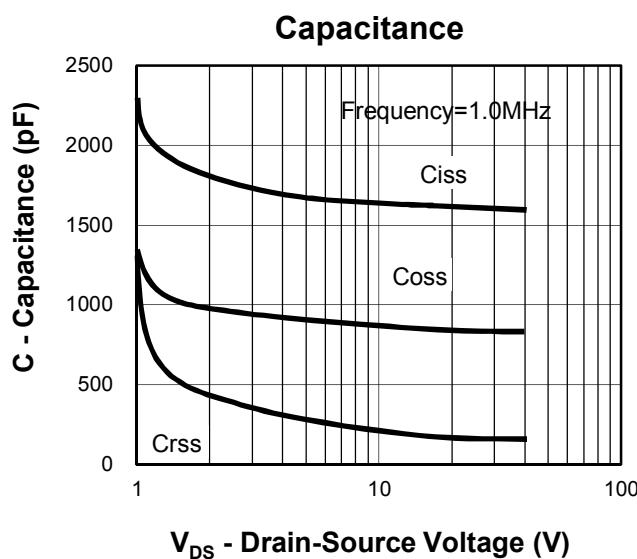
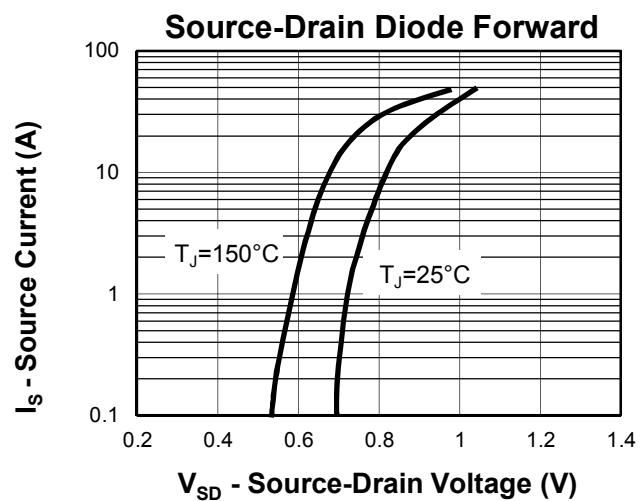
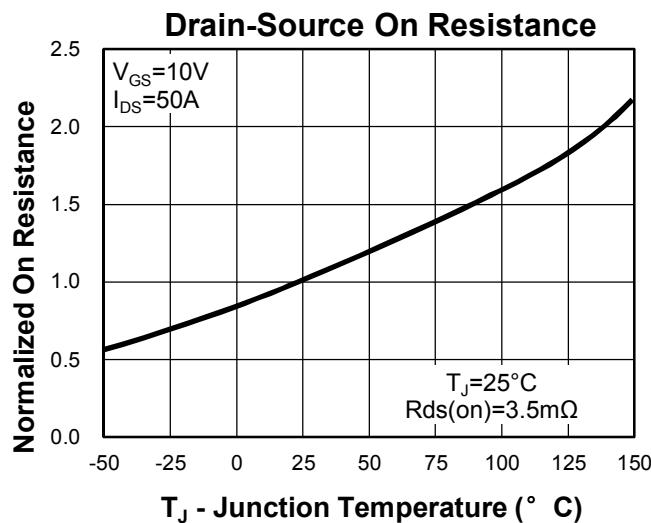
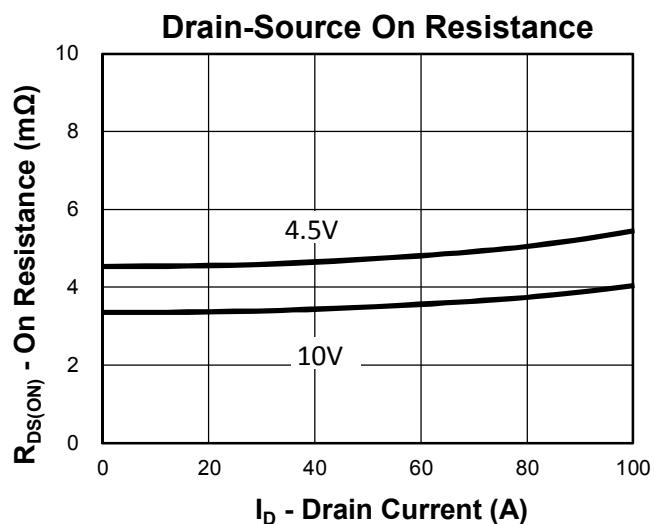
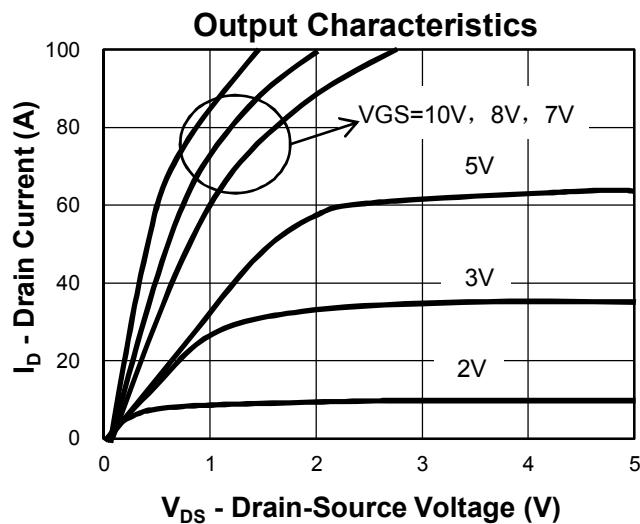
Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
Static Electrical Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$, $I_{\text{D}}=250\mu\text{A}$	40	---	---	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}}=40\text{V}$, $V_{\text{GS}}=0\text{V}$	---	---	1	μA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$, $I_{\text{D}}=250\mu\text{A}$	1.0	---	2.5	V
I_{GSS}	Gate Leakage Current	$V_{\text{GS}}=\pm 20\text{V}$, $V_{\text{DS}}=0\text{V}$	---	---	± 100	nA
$R_{\text{DS(ON)}}$	Drain-Source On-state Resistance	$V_{\text{GS}}=10\text{V}$, $I_{\text{D}}=50\text{A}$	---	3.5	4.5	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}$, $I_{\text{D}}=35\text{A}$	---	4.5	5.5	$\text{m}\Omega$
Dynamic Characteristics^⑤						
C_{iss}	Input Capacitance	$V_{\text{DS}}=20\text{V}$, $V_{\text{GS}}=0\text{V}$, Freq.:1MHz	---	1560	---	pF
C_{oss}	Output Capacitance		---	780	---	
C_{rss}	Reverse Transfer Capacitance		---	80	---	
$T_{\text{d(on)}}$	Turn-on Delay Time	$V_{\text{DS}}=20\text{V}, V_{\text{GS}}=10\text{V}$, $I_{\text{D}}=50\text{A}, R_{\text{G}}=4.7\Omega$	---	13	---	nS
T_r	Turn-on Rise Time		---	21	---	
$T_{\text{d(off)}}$	Turn-off Delay Time		---	29	---	
T_f	Turn-off Fall Time		---	9	---	
Q_g	Total Gate Charge	$V_{\text{DS}}=32\text{V}, V_{\text{GS}}=10\text{V}$, $I_{\text{D}}=50\text{A}$	---	28	---	nC
Q_{gs}	Gate-Source Charge		---	5	---	
Q_{gd}	Gate-Drain Charge		---	9	---	
Source-Drain Characteristics						
V_{SD}	Diode Forward Voltage	$I_{\text{S}}=50\text{A}$, $V_{\text{GS}}=0\text{V}$	---	---	1.2	V
t_{rr}	Reverse Recovery Time	$I_{\text{F}}=50\text{A}$, $V_{\text{GS}}=0\text{V}$, $dI_{\text{F}}/dt=100\text{A}/\mu\text{s}$	---	18	---	nS
Q_{rr}	Reverse Recovery Charge		---	29	---	nC

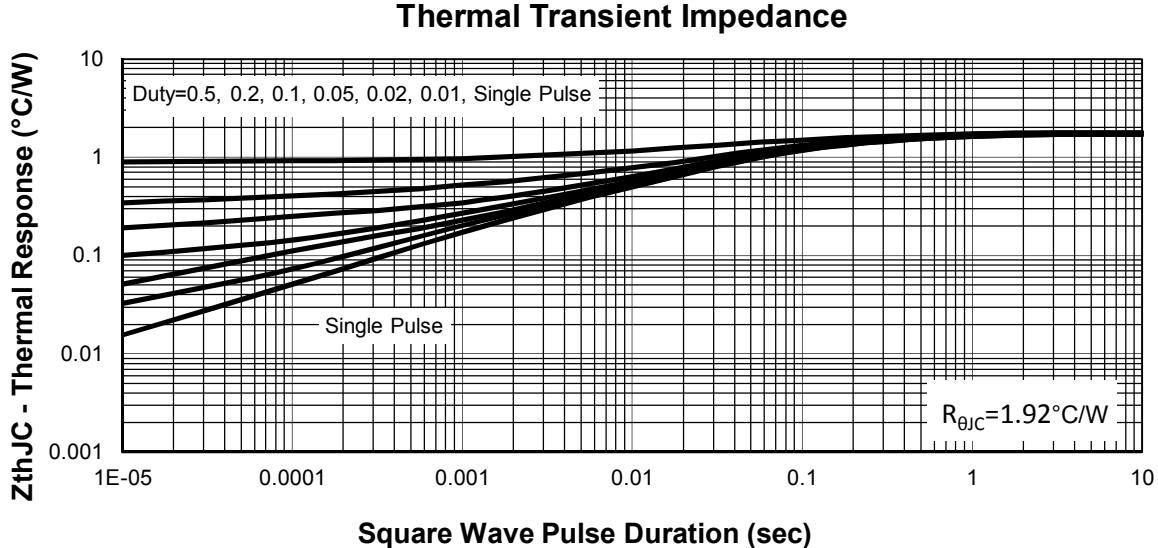
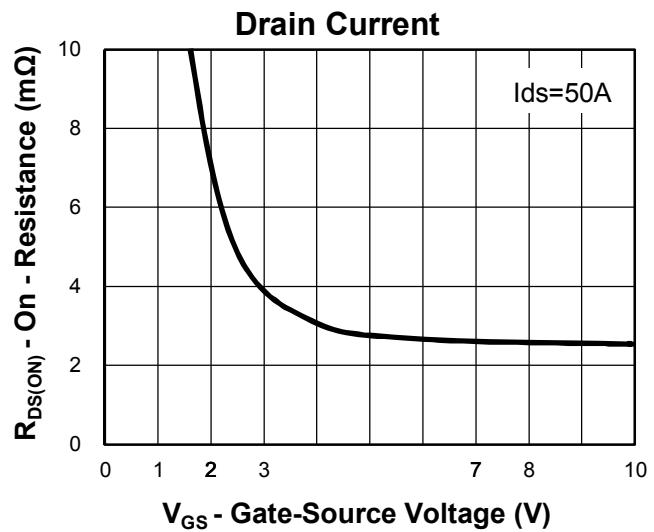
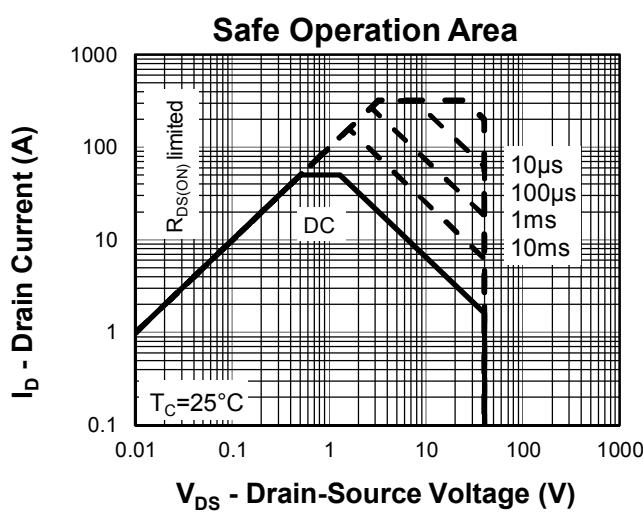
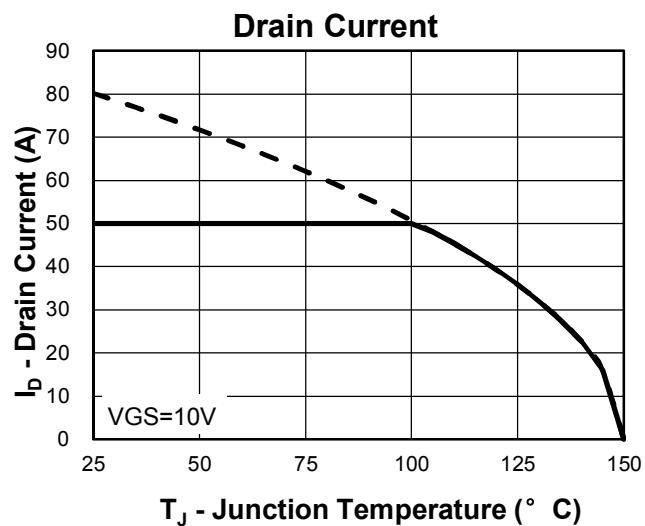
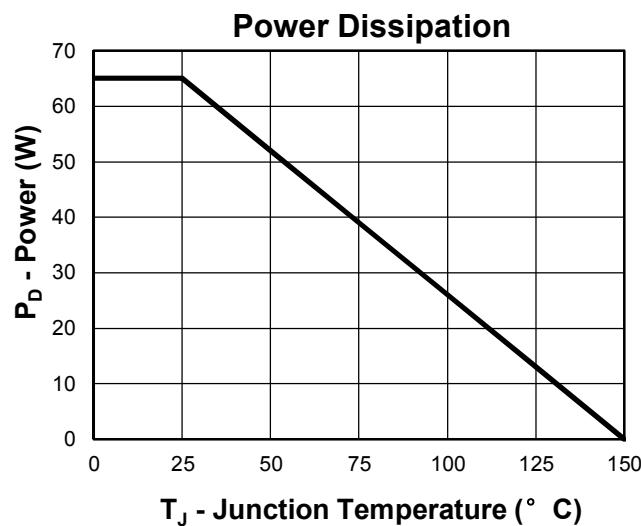
Note ④ : Pulse test (pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$).

Note ⑤ : Guaranteed by design, not subject to production testing.

N-Channel Enhancement Mode MOSFET

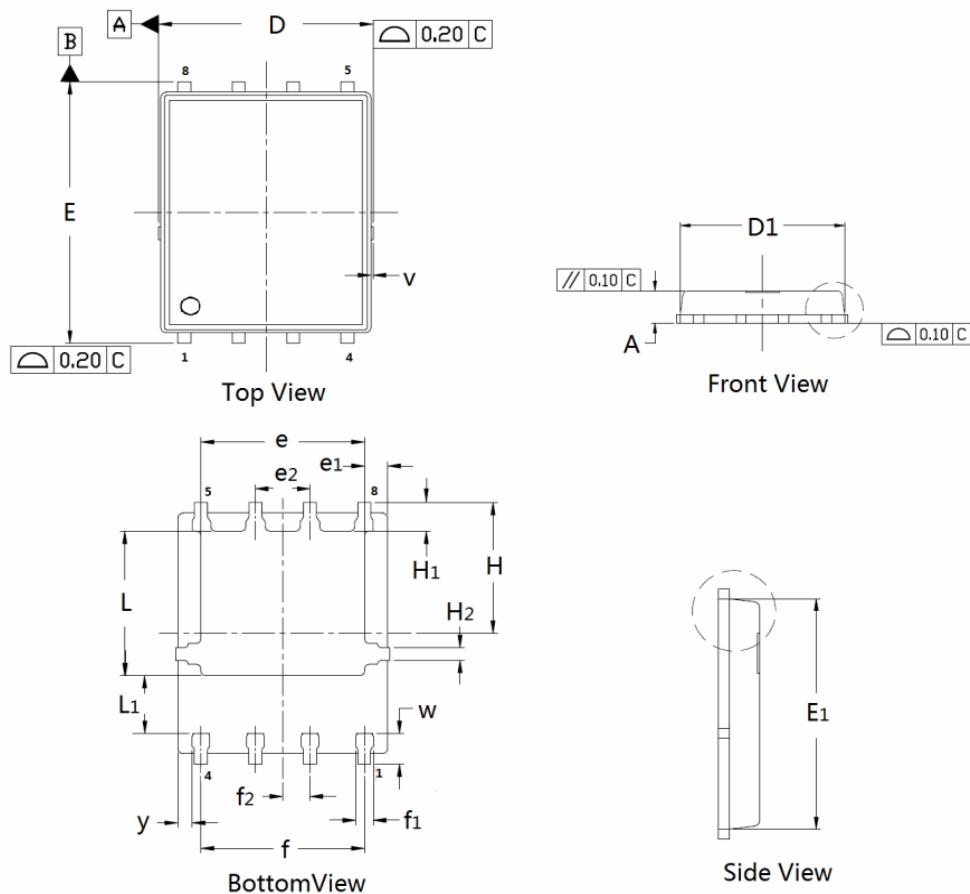
Typical Characteristics



N-Channel Enhancement Mode MOSFET


N-Channel Enhancement Mode MOSFET

DFN5×6 Package Outline Data



DIMENSIONS (unit : mm)

Symbol		Typ	Max	Symbol	Min	Typ	Max
A	0.90	1.02	1.10	D	4.90	4.98	5.10
D₁	4.80	4.89	5.10	E	5.90	6.11	6.25
E₁	5.65	5.74	5.95	e	3.72	3.80	3.92
e₁	--	0.5	--	e₂	--	1.	--
f	--	3.8	--	f₁	0.31	0.37	0.51
f₂	--	0.6	--	H	--	3.	--
H₁	0.59	0.63	0.79	H₂	0.26	0.28	0.32
L	3.35	3.45	3.65	L₁	--	1.	--
V	--	0.1	--	w	0.64	0.68	0.84
y	--	0.3	--		--		--